


<b>Search Notes</b>  	<b>Application/Control No.</b>  10697122	<b>Applicant(s)/Patent Under Reexamination</b>  CHANG ET AL.
	<b>Examiner</b>  Nguyen, Jennifer T	<b>Art Unit</b>  2629

SEARCHED			
Class	Subclass	Date	Examiner
345	102, 207, 211,87-89,204	6/14/07	JN

SEARCH NOTES		
Search Notes	Date	Examiner
East search, JPO, PG-PUB,IEEE, inventor names, claim interference	6/14/07	JN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
349	112-119	6/14/07	JN
359	245,290	6/14/07	JN
438	257	6/14/07	JN